

Probing Stations



DESCRIPTION

We offer probing and inspection systems over a patented adaptive architecture. Unlike traditional probe systems, all of the basic components of our systems are interchangeable, upgradable, and configurable.

Systems are available to handle products from 50mm to 300mm, and are available in manual, semiautomatic, and fully automatic configurations. Our systems have ability to be upgraded at any point in its life cycle as your product needs or volume requirements change. As the customer's business environment or test conditions change, we can be rapidly reconfigured to meet these new requirements. Changes to wafer size, automation level, or test procedure do not translate into a need for new capital equipment. This substantially reduces the cost of new product development and the time to procure the appropriate test equipment. Reconfigurations are typically performed in the field, at the customer site.

